

Active redundancy in fault tolerance : A modular switch level solution with synchronous switching

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Active redundancy in isolated DC-DC converters: A modular solution for fault tolerance

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AdAM: Adaptive Approximate Multiplier for Fault Tolerance in DNN Accelerators

Taheri, Mahdi; **Cherezova, Natalia**; Nazari, Samira; **Azarpeyvand, Ali**; **Ghasempouri, Tara**; **Daneshtalab, Masoud**; **Raik, Jaan**; **Jenihhin, Maksim** IEEE transactions on device and materials reliability 2024 / p. 66-75 : ill <https://doi.org/10.1109/TDMR.2024.3523386>

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